## ATOMIC FORCE

## MICROSCOPY

Featuring an innovational ergonomic design and improved electronics, this scientific microscope delivers atomic-scale resolution at a remarkably affordable price, making it an ideal choice for education as well as research. The NAMA-AFM offers educators an exceptional opportunity to introduce their students to many powerful SPM/AFM techniques.

## Application

- Data storage devices (data storage media inspection)
- Micro and nanostructures (gratings, self-organizing systems)
- Materials science
- Polymers
- Medical applications
- Semiconductors
- Thin films


## 50 <br> Advantages

- Cost-effective platform offers simple upgrade path
- Excellent educational instrument with course curriculum


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## Features

- Contact mode
- Noncontact mode
- Semi Contact


## SCANNING TUNNELING

## MICROSCOPY

## Features:



- Automatic mechanism to approach sample
- Automatic sample and camera moving by software
- Capability of spectroscopy to verify the material type with I-Z and I-V modes at desired point of surface of sample
- Engraving of nanometer-scale surface by lithography (manually or by importing the pattern images from the desired file
- Ability of tilting (adjusting X, Y axis in sample)
- Capability to change size, angle and location of image by software without handling the sample and ability of automatic offset calculation
- Ability to analyze the image independently from the scanning
- Ability to apply custom filters in three stages on the data and possibility of retrieving the data
- Capability to take the repeated imaging without user intervention and possibility of changing conditions of imaging automatically
- Ability to export result, which is compatible with other softwares (txt. file)
- Ability to storage all data of scanning with image or spectroscopy curves.
- And more features such as:
- Advanced mechanical design with very low thermal drift and the ability to view online height and current during scanning
- Imaging capability in both constant height and constant current modes with minimum electronic noise.
- Ability to change the parameters of the PID, Current and voltage during imaging
- Provide 2D and 3D images at nanometer-scale simultaneously (such as biological molecules, DNA, Antibody and nanomaterial)
- Ability to display multiple clear and accurate 2D and 3D image files in order to compare them (for study on changing the status of polymers over the time
- Ability to measure the size of material on the image
- Hardware zoom capability for desired more detailed image.
- Software zoom capability for desired area
- Ability to customize the color of image file Specification


## Advantages

- Expandable to suite user needs
- Designed for quick and reliable
measurements by experts and novices alike
- Unique price/performance ratio for research and teaching
- Mechanical Stability
- Thermal drift balance
- Low Electronic noise
- Ergonomic Design
- Windows-Based Powerful Software

Easy Maintenance


## STM Software

| Various charts of the scan data online | 2D view Image, Line graph, spectroscopy <br> (I-V, I-Z) |
| :--- | :--- |
| Various charts of the image data offline | 2D view,3D view, Line Profile, Color map |
| Various charts of the spectroscopy (I-V, I-Z)data offline | Line Graph, first and second derivative, ... |
| Noise reduction and feature enhancement | Data filtering in three levels |
| Lithography pattern | 16 Color BMP and .dxf files |
| View all maximum scan range and change parameter |  |
| very user friendly |  |
| Data export | TXT,BMP,JPEG,GIF, ... |
| Automatic image transfer to offline processing software |  |

## ELECTRONICS

| Electronics size | $55 * 55^{*} 18 \mathrm{~cm}$ |
| :--- | :--- |
| Power supply | $220 \mathrm{~V} \sim / 50 \mathrm{~Hz} / \mathrm{AA}$ |
| Computer Interface | 16 bit Data Acquisition Hardware |
| Scan Speed | Up to 100 Line/s at 128 data point / line |
| Scan image rotation | $0-360^{\circ}$ |
| Sample tilt | Automatically by software |
| Spectroscopy modes | Single point measurement |
| Spectroscopy data point | Up to 2000 |

STM Measurment

| Maximum Scan range | $8 \mu \mathrm{~m}( \pm 4000 \mathrm{~nm})$ |
| :--- | :--- |
| Maximum Z-range | $3 \mu \mathrm{~m}( \pm 1500 \mathrm{~nm})$ |
| Derive resolution Z | 0.045 nm |
| Derive resolution XY | 0.12 nm |
| Current set point | $0.02-100 \mathrm{nA}$ in 3 pA steps |
| Imaging modes | Constant current(Topography), Constant Height (Current) |
| Spectroscopy modes | Current-Voltage, Current-Distance |
| Lithography modes | Bitmap, Vector and Manual |
| Tip voltage | $\pm 10 \mathrm{~V}$ in 0.3 mV steps |
| Sample approach | Fully automatic and manually |
| Sample size | Max 20 mm diameter |

